

Invented and patented multiple characterization methods for diagnostics and optimization of semiconductor-device processing

Over 20 invented (and mostly patented) methods of semiconductor materials and devices characterization for diagnostics and optimization of their processing, based on electron microscopy, photoelectric and electrical measurements.

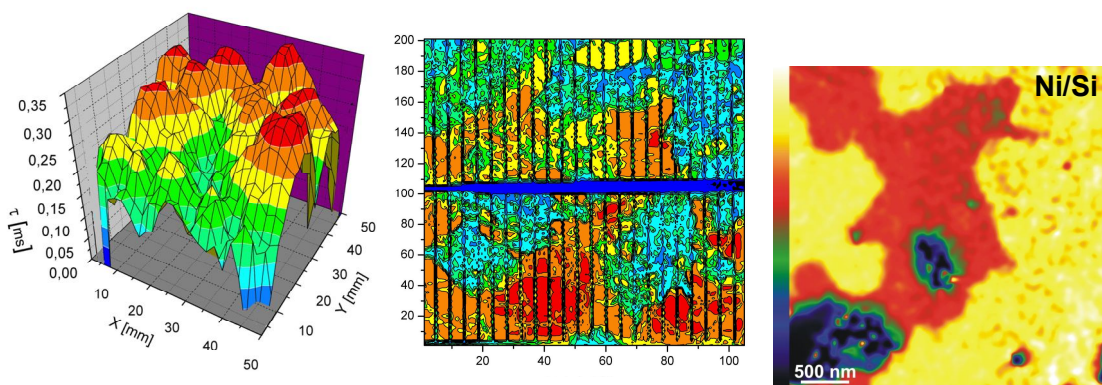


Fig. 3-D plot and 2-D map of minority carrier lifetime in silicon wafers, derived from minority carrier lifetime measurements with use of microwave photoconductance decay following a laser pulse, and map of Ni/Zr concentration ratio in ohmic contact to SiC sample, derived from XEDS measurements in TEM (from left to right)